# **PHN210T**

### **Dual N-channel TrenchMOS intermediate level FET**

Rev. 02 — 15 December 2010

**Product data sheet** 

### 1. Product profile

### 1.1 General description

Dual intermediate level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

#### 1.2 Features and benefits

- Suitable for high frequency applications due to fast switching characteristics
- Suitable for logic level gate drive sources
- Suitable for low gate drive sources

### 1.3 Applications

- DC-to-DC converters
- Logic level translators

Motor and relay drivers

#### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25$ °C; $T_j \le 150$ °C; Repetitive peak drain-source voltage		-	-	30	V
$I_D$	drain current	T <sub>sp</sub> = 25 °C; Single device	<u>[1]</u>	-	-	3.4	Α
P <sub>tot</sub>	total power dissipation	$T_{sp} = 25  ^{\circ}\text{C}$	[2]	-	-	2	W
Static chara	acteristics						
R <sub>DSon</sub>	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 1 \text{ A};$ $T_j = 25 \text{ °C}$		-	120	200	mΩ
	resistance	$V_{GS} = 10 \text{ V; } I_D = 2.2 \text{ A;}$ $T_j = 25 \text{ °C}$		-	80	100	mΩ
Dynamic characteristics							
$Q_{GD}$	gate-drain charge	$V_{GS} = 10 \text{ V; } I_D = 2.3 \text{ A;}$ $V_{DS} = 15 \text{ V; } T_j = 25 \text{ °C}$		-	0.7	-	nC

<sup>[1]</sup> Surface mounted on FR4 board, t ≤ 10 sec.



<sup>[2]</sup> Surface mounted on FR4, t ≤ 10 sec.

#### **Dual N-channel TrenchMOS intermediate level FET**

### 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S1	source1		D. D. D. D. D.
2	G1	gate1	8 <u>月 月 月</u> 5	D1 D1 D2 D2
3	S2	source2		
4	G2	gate2		
5	D	drain2	1	
6	D	drain2	SOT96-1 (SO8)	S1 G1 S2 G2
7	D	drain1		mbk725
8	D	drain1		

## 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PHN210T	SO8	plastic small outline package; 8 leads; body width 3.9 mm	SOT96-1

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## 4. Limiting values

Table 4. Limiting values

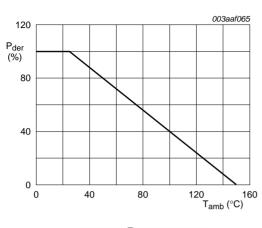
In accordance with the Absolute Maximum Rating System (IEC 60134).

$ \begin{array}{ c c c c } \hline \textbf{Symbol} & \textbf{Parameter} & \textbf{Conditions} & \textbf{Min} & \textbf{Max} & \textbf{Unit} \\ \hline \textbf{V}_{DS} & \text{drain-source voltage} & \textbf{Continuous} & - & 30 & V \\ \hline \textbf{T}_{j} \geq 25 \text{ °C; T}_{j} \leq 150 \text{ °C; Repetitive peak} & - & 30 & V \\ \hline \textbf{V}_{DGR} & \text{drain-gate voltage} & \textbf{R}_{GS} = 20 \text{ k}\Omega & - & 30 & V \\ \hline \textbf{V}_{DS} & \text{gate-source voltage} & -20 & 20 & V \\ \hline \textbf{I}_{D} & \text{drain current} & \textbf{T}_{sp} = 70 \text{ °C; Dual device} & 11 & - & 1.9 & A \\ \hline \textbf{T}_{sp} = 70 \text{ °C; Single device} & 11 & - & 2.8 & A \\ \hline \textbf{T}_{sp} = 25 \text{ °C; Dual device} & 11 & - & 2.4 & A \\ \hline \textbf{T}_{sp} = 25 \text{ °C; Dual device} & 11 & - & 3.4 & A \\ \hline \textbf{I}_{DM} & \text{peak drain current} & \textbf{T}_{sp} = 25 \text{ °C; pulsed} & - & 14 & A \\ \hline \textbf{P}_{tot} & \text{total power dissipation} & \textbf{T}_{sp} = 25 \text{ °C; pulsed} & - & 14 & A \\ \hline \textbf{P}_{tot} & \text{total power dissipation} & \textbf{T}_{sp} = 25 \text{ °C} & 12 & - & 2 & W \\ \hline \textbf{T}_{stg} & \text{storage temperature} & -65 & 150 & \text{°C} \\ \hline \textbf{Source-drain diode} & \textbf{I}_{sm} & \text{peak source current} & \textbf{T}_{sp} = 25 \text{ °C} & 12 & - & 2.2 & A \\ \hline \textbf{I}_{SM} & \text{peak source current} & \textbf{T}_{sp} = 25 \text{ °C} & \text{pulsed} & - & 14 & A \\ \hline \textbf{Avalanche rugedeness} & \textbf{T}_{sp} = 25 \text{ °C} & \text{pulsed} & - & 14 & A \\ \hline \textbf{Avalanche rugedeness} & \textbf{I}_{SM} & \text{peak source drain-source} & \textbf{V}_{OS} = 10 \text{ V; T}_{j(init)} = 25 \text{ °C; I}_{D} = 3.4 \text{ A;} \\ \textbf{V}_{OD} \leq 15 \text{ V; unclamped; R}_{GS} = 50 \Omega; _{c} = 0.2 \text{ ms} \\ \hline \textbf{I}_{AD} & \text{non-repetitive drain-source} & \textbf{V}_{Sup} \leq 15 \text{ V; V}_{CS} = 10 \text{ V; T}_{j(init)} = 25 \text{ °C; I}_{D} = 3.4 \text{ A;} \\ \textbf{V}_{OD} \leq 15 \text{ V; unclamped; R}_{GS} = 50 \Omega; _{c} = 0.2 \text{ ms} \\ \hline \textbf{I}_{AD} & \text{non-repetitive avalanche} & \textbf{V}_{Sup} \leq 15 \text{ V; V}_{CS} = 10 \text{ V; T}_{j(init)} = 25 \text{ °C; I}_{D} = 3.4 \text{ A;} \\ \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} \\ \hline \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} \\ \hline \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} \\ \hline \textbf{A}_{CUT} & \textbf{A}_{CUT} & \textbf{A}_{CUT} & A$							
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	Symbol	Parameter	Conditions		Min	Max	Unit
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$V_{DS}$	drain-source voltage	Continuous		-	30	V
$V_{GS} \qquad \text{gate-source voltage} \qquad \qquad \begin{array}{c ccccccccccccccccccccccccccccccccccc$			, ,		-	30	V
$I_{D} \  \    \frac{T_{sp} = 70 \text{ °C; Dual device}}{T_{sp} = 70 \text{ °C; Dual device}} \  \   \frac{11}{11} \  \   - \  \   1.9  A \  \   \frac{T_{sp} = 70 \text{ °C; Single device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{11}{11} \  \   - \  \   2.8  A \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{11}{11} \  \   - \  \   2.4  A \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{11}{11} \  \   - \  \   3.4  A \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{11}{11} \  \   - \  \   3.4  A \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{11}{11} \  \   - \  \   3.4  A \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{11}{11} \  \   - \  \   3.4  A \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{11}{11} \  \   - \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{11}{11} \  \   - \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{11}{11} \  \   - \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{sp} = 25 \text{ °C; Dual device}} \  \   \frac{T_{sp} = 25 \text{ °C; Dual device}}{T_{s$	$V_{DGR}$	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	30	V
$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	V <sub>GS</sub>	gate-source voltage			-20	20	V
$ T_{sp} = 25  ^{\circ}\text{C};  \text{Dual device} \qquad \begin{array}{c ccccccccccccccccccccccccccccccccccc$	I <sub>D</sub>	drain current	T <sub>sp</sub> = 70 °C; Dual device	<u>[1]</u>	-	1.9	Α
$T_{sp} = 25  ^{\circ}\text{C};  \text{Single device} \qquad \begin{array}{ccccccccccccccccccccccccccccccccccc$			T <sub>sp</sub> = 70 °C; Single device	<u>[1]</u>	-	2.8	Α
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$			T <sub>sp</sub> = 25 °C; Dual device	<u>[1]</u>	-	2.4	Α
$\begin{array}{cccccccccccccccccccccccccccccccccccc$			T <sub>sp</sub> = 25 °C; Single device	<u>[1]</u>	-	3.4	Α
$T_{stg} \qquad \text{storage temperature} \qquad \qquad -65 \qquad 150  ^{\circ}\text{C}$ $T_{j} \qquad \text{junction temperature} \qquad \qquad -65 \qquad 150  ^{\circ}\text{C}$ $\textbf{Source-drain diode}$ $I_{S} \qquad \text{source current} \qquad T_{sp} = 25  ^{\circ}\text{C} \qquad \qquad - \qquad 2.2  \text{A}$ $I_{SM} \qquad \text{peak source current} \qquad T_{sp} = 25  ^{\circ}\text{C}; \text{pulsed} \qquad \qquad - \qquad 14  \text{A}$ $\textbf{Avalanche ruggedness}$ $E_{DS(AL)S} \qquad \text{non-repetitive drain-source} \qquad V_{GS} = 10  \text{V}; T_{j(init)} = 25  ^{\circ}\text{C}; I_{D} = 3.4  \text{A}; \\ \text{avalanche energy} \qquad V_{DD} \leq 15  \text{V}; \text{unclamped}; R_{GS} = 50  \Omega; \\ t_{p} = 0.2  \text{ms}$ $I_{AS} \qquad \text{non-repetitive avalanche} \qquad V_{sup} \leq 15  \text{V}; V_{GS} = 10  \text{V}; T_{j(init)} = 25  ^{\circ}\text{C}; \qquad - \qquad 3.4  \text{A}$	I <sub>DM</sub>	peak drain current	$T_{sp}$ = 25 °C; pulsed		-	14	Α
$T_{j} \qquad \text{junction temperature} \qquad \qquad -65 \qquad 150  ^{\circ}\text{C}$ $ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	P <sub>tot</sub>	total power dissipation	T <sub>sp</sub> = 25 °C	[2]	-	2	W
	T <sub>stg</sub>	storage temperature			-65	150	°C
$\begin{array}{llllllllllllllllllllllllllllllllllll$	Tj	junction temperature			-65	150	°C
$\begin{split} & I_{SM} & \text{peak source current} & T_{sp} = 25 \text{ °C; pulsed} & - & 14 & A \\ & \textbf{Avalanche ruggedness} \\ & E_{DS(AL)S} & \text{non-repetitive drain-source} & V_{GS} = 10 \text{ V; } T_{j(init)} = 25 \text{ °C; } I_D = 3.4 \text{ A;} & - & 13 & \text{mJ} \\ & V_{DD} \leq 15 \text{ V; unclamped; } R_{GS} = 50 \text{ \Omega;} & & & & & \\ I_{AS} & \text{non-repetitive avalanche} & V_{sup} \leq 15 \text{ V; } V_{GS} = 10 \text{ V; } T_{j(init)} = 25 \text{ °C;} & - & 3.4 & A \end{split}$	Source-drain	diode					
$\label{eq:local_problem} \begin{array}{cccccccccccccccccccccccccccccccccccc$	Is	source current	T <sub>sp</sub> = 25 °C		-	2.2	Α
$ \begin{array}{c} {\sf E}_{\sf DS(AL)S} &  \text{non-repetitive drain-source} \\  \text{avalanche energy} &  {\sf V}_{\sf GS} = 10 \; {\sf V}; \; {\sf T}_{j(\text{init})} = 25 \; {\sf ^{\circ}C}; \; {\sf I}_{\sf D} = 3.4 \; {\sf A}; \\  {\sf V}_{\sf DD} \leq 15 \; {\sf V}; \; {\sf unclamped}; \; {\sf R}_{\sf GS} = 50 \; \Omega; \\  {\sf t}_{\sf p} = 0.2 \; {\sf ms} \\ \\ \\ {\sf I}_{\sf AS} &  {\sf non-repetitive avalanche} &  {\sf V}_{\sf sup} \leq 15 \; {\sf V}; \; {\sf V}_{\sf GS} = 10 \; {\sf V}; \; {\sf T}_{j(\text{init})} = 25 \; {\sf ^{\circ}C}; \\  -  3.4  {\sf A} \\ \end{array} $	I <sub>SM</sub>	peak source current	T <sub>sp</sub> = 25 °C; pulsed		-	14	Α
avalanche energy $V_{DD} \le 15 \text{ V; unclamped; } R_{GS} = 50 \Omega;$ $t_p = 0.2 \text{ ms}$ $I_{AS} \qquad \text{non-repetitive avalanche} \qquad V_{sup} \le 15 \text{ V; } V_{GS} = 10 \text{ V; } T_{j(init)} = 25 \text{ °C;} \qquad - \qquad 3.4 \qquad A$	Avalanche ru	ggedness					
	E <sub>DS(AL)S</sub>	•	$V_{DD} \le 15 \text{ V}$ ; unclamped; $R_{GS} = 50 \Omega$ ;		-	13	mJ
	I <sub>AS</sub>	•			-	3.4	Α

<sup>[1]</sup> Surface mounted on FR4 board, t ≤ 10 sec.

<sup>[2]</sup> Surface mounted on FR4, t ≤ 10 sec.

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$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100 \%$$

Fig 1. Normalized total power dissipation as a function of ambient temperature

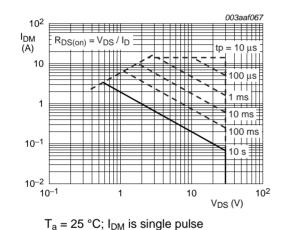
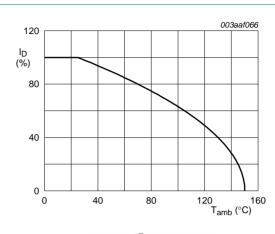


Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}\text{C})}} \times 100\%$$

Fig 2. Normalized continuous drain current as a function of ambient temperature

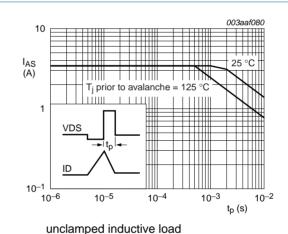


Fig 4. Single-shot avalanche rating; avalanche current as a function of avalanche period

#### **Dual N-channel TrenchMOS intermediate level FET**

### 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance	Surface mounted; FR4 board	-	150	-	K/W
	from junction to ambient	Surface mounted; FR4 board; t ≤ 10 sec	-	-	62.5	K/W

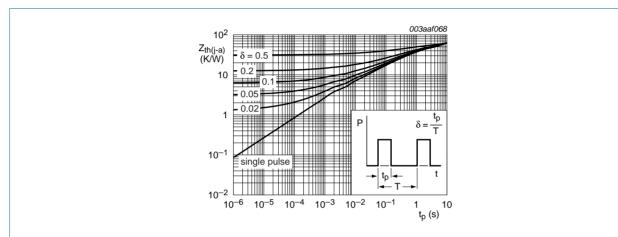


Fig 5. Transient thermal impedance from junction to ambient as a function of pulse duration

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#### **Dual N-channel TrenchMOS intermediate level FET**

### 6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
_	racteristics			<b>7</b> F		
V <sub>(BR)DSS</sub>	drain-source	$I_D = 10 \mu A; V_{GS} = 0 V; T_i = 25 °C$	30	-	-	V
(2.1)200	breakdown voltage	$I_D = 10 \mu A; V_{GS} = 0 V; T_i = -55 °C$	27	-	-	V
V <sub>GS(th)</sub>	gate-source threshold	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_i = -55 \text{ °C}$	-	-	3.2	V
	voltage	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>i</sub> = 150 °C	0.4	-	-	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_i = 25 \text{ °C}$	1	2	2.8	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 24 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nA
		$V_{DS} = 24 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	0.6	10	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nΑ
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	100	nΑ
R <sub>DSon</sub>	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 1 \text{ A}; T_j = 25 ^{\circ}\text{C}$	-	120	200	mΩ
	resistance	$V_{GS} = 10 \text{ V}; I_D = 2.2 \text{ A}; T_j = 150 \text{ °C}$	-	-	170	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 2.2 \text{ A}; T_j = 25 \text{ °C}$	-	80	100	mΩ
I <sub>DSon</sub>	on-state drain current	V <sub>DS</sub> = 1 V; V <sub>GS</sub> = 10 V	3.5	-	-	Α
		$V_{DS} = 5 \text{ V}; V_{GS} = 4.5 \text{ V}$	2	-	-	Α
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 2.3 \text{ A}; V_{DS} = 15 \text{ V}; V_{GS} = 10 \text{ V};$	-	6	-	nC
$Q_{GS}$	gate-source charge	T <sub>j</sub> = 25 °C	-	0.7	-	nC
$Q_{GD}$	gate-drain charge		-	0.7	-	nC
C <sub>iss</sub>	input capacitance	$V_{DS} = 20 V; V_{GS} = 0 V; f = 1 MHz;$	-	250	-	pF
Coss	output capacitance	T <sub>j</sub> = 25 °C	-	88	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	54	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 20 \text{ V}; R_L = 18 \Omega; V_{GS} = 10 \text{ V};$	-	6	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 6 \Omega; T_j = 25 °C$	-	8	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	21	-	ns
t <sub>f</sub>	fall time		-	15	-	ns
9fs	transfer conductance	$V_{DS} = 20 \text{ V}; I_D = 2.2 \text{ A}; T_j = 25 ^{\circ}\text{C}$	2	4.5	-	S
L <sub>D</sub>	internal drain inductance	measured from drain lead to centre of die; $T_j = 25$ °C	-	2.5	-	nΗ
L <sub>S</sub>	internal source inductance	measured from source lead to source bond pad; $T_j = 25$ °C	-	5	-	nΗ
Source-di	rain diode					
$V_{SD}$	source-drain voltage	$I_S = 1.25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.82	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 1.25 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$	-	69	-	ns
Qr	recovered charge	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; T_j = 25 \text{ °C}$	_	55	_	nC

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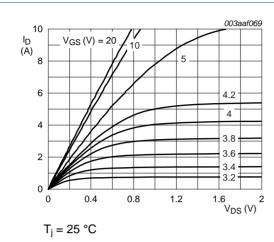


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values

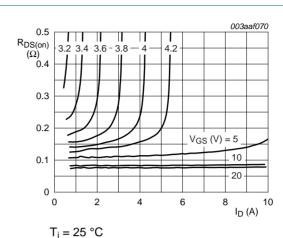


Fig 7. Drain-source on-state resistance as a function of drain current; typical values

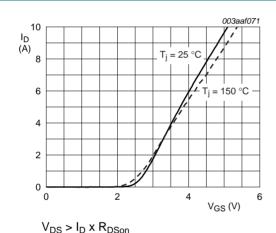


Fig 8. Transfer characteristics: drain current as a function of gate-source voltage; typical values

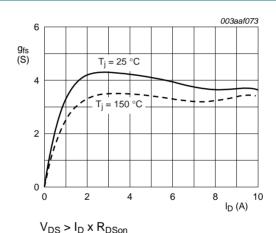
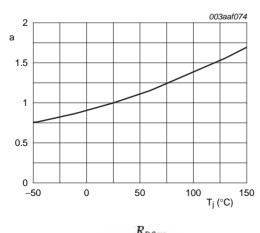


Fig 9. Forward transconductance as a function of drain current; typical values



 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$ 

Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature

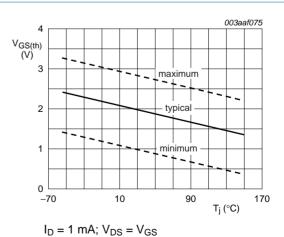


Fig 11. Gate-source threshold voltage as a function of junction temperature

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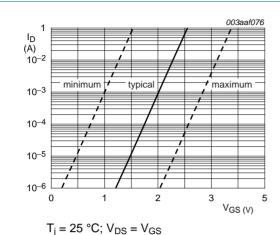
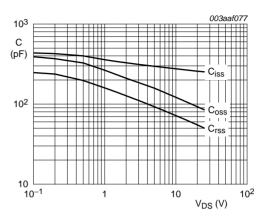


Fig 12. Sub-threshold drain current as a function of gate-source voltage



 $V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$ 

Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

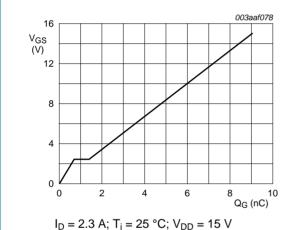
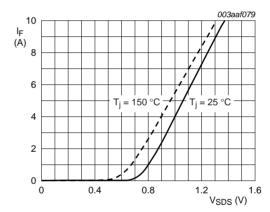


Fig 14. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0 V$ 

Fig 15. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

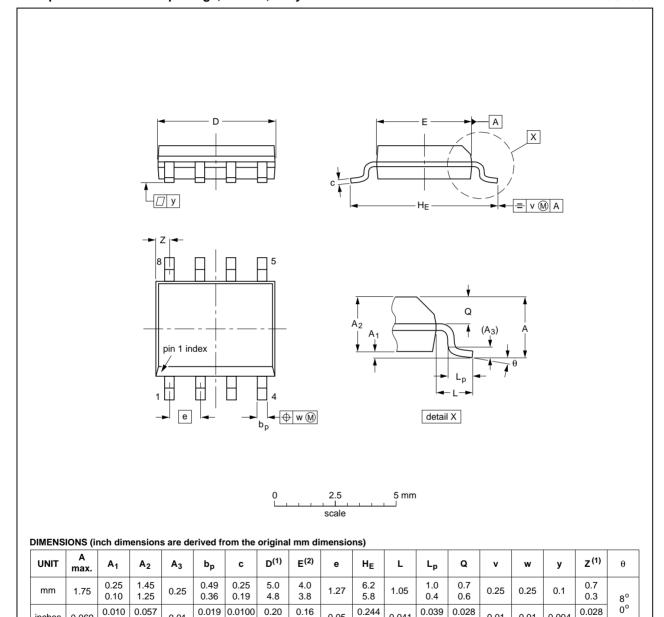
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### **Package outline**

#### SO8: plastic small outline package; 8 leads; body width 3.9 mm

SOT96-1



inches

1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.

0.019 0.0100

0.014 0.0075

0.20

0.16

0.15

2. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT96-1	076E03	MS-012			<del>99-12-27</del> 03-02-18

0.05

0.244

0.228

0.041

0.039

0.016

0.028

0.024

0.01

0.01

0.004

Fig 16. Package outline SOT96-1 (SO8)

0.010

0.004

0.069

0.057

0.049

0.01

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### 8. Revision history

#### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
PHN210T v.2	20101215	Product data sheet	-	PHN210T v.1	
Modifications:		rmat of this data sheet has been redesigned to comply with the new identity guideline? Semiconductors.			
	<ul> <li>Legal texts have</li> </ul>	ve been adapted to the new	company name where	appropriate.	
PHN210T v.1	19990301	Product specification	-	-	

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### 9. Legal information

#### 9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <a href="http://www.nxp.com">http://www.nxp.com</a>.

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